

MOSFET

950V CoolMOS™ P7 SJ Power Device

The latest 950V CoolMOS™ P7 series sets a new benchmark in 950V super junction technologies and combines best-in-class performance with state-of-the-art ease-of-use, resulting from Infineon's over 18 years pioneering super junction technology innovation.

Features

- Best-in-class FOM $R_{DS(on)} * E_{oss}$; reduced Q_g , C_{iss} , and C_{oss}
- Best-in-class DPAK $R_{DS(on)}$
- Best-in-class $V_{GS(th)}$ of 3V and smallest $V_{GS(th)}$ variation of $\pm 0.5V$
- Integrated Zener Diode ESD protection
- Best-in-class CoolMOS™ quality and reliability
- Fully optimized portfolio

Benefits

- Best-in-class performance
- Enabling higher power density designs, BOM savings and lower assembly costs
- Easy to drive and to parallel
- Better production yield by reducing ESD related failures
- Less production issues and reduced field returns
- Easy to select right parts for fine tuning of designs

Potential applications

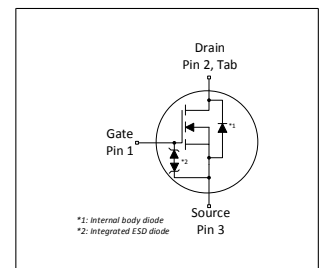
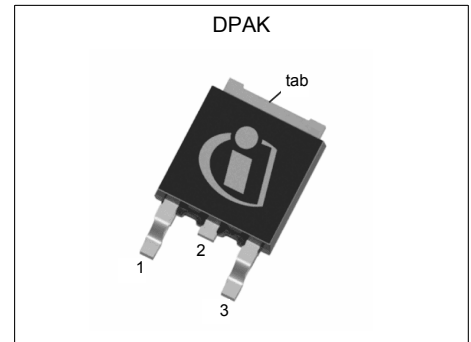
Recommended for flyback topologies for LED Lighting, low power Chargers and Adapters, Smart Meter, AUX power and Industrial power. Also suitable for PFC stage in Consumer and Solar applications.

Product Validation: Fully qualified acc. JEDEC for Industrial Applications

Product validation

Fully qualified according to JEDEC for Industrial Applications

Please note: For MOSFET paralleling the use of ferrite beads on the gate or separate totem poles is generally recommended.



RoHS

Table 1 Key Performance Parameters

Parameter	Value	Unit
$V_{DS} @ T_J=25^{\circ}C$	950	V
$R_{DS(on),max}$	1.2	Ω
$Q_{g,typ}$	15	nC
I_D	6	A
$E_{oss} @ 500V$	1.3	μJ
$V_{GS(th),typ}$	3	V
ESD class (HBM)	2	-

Type / Ordering Code	Package	Marking	Related Links
IPD95R1K2P7	PG-TO252-3	95R1K2P7	see Appendix A

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1 Maximum ratings

at $T_j = 25^\circ\text{C}$, unless otherwise specified

Table 2 Maximum ratings

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Continuous drain current ¹⁾	I_D	-	-	6 3.7	A	$T_C=25^\circ\text{C}$ $T_C=100^\circ\text{C}$
Pulsed drain current ²⁾	$I_{D,pulse}$	-	-	16	A	$T_C=25^\circ\text{C}$
Avalanche energy, single pulse	E_{AS}	-	-	11	mJ	$I_D=0.7\text{A}$; $V_{DD}=50\text{V}$; see table 10
Avalanche energy, repetitive	E_{AR}	-	-	0.14	mJ	$I_D=0.7\text{A}$; $V_{DD}=50\text{V}$; see table 10
Application (Flyback) relevant avalanche current, single pulse ³⁾	I_{AS}	-	3.0	-	A	measured with standard leakage inductance of transformer of $10\mu\text{H}$
MOSFET dv/dt ruggedness	dv/dt	-	-	100	V/ns	$V_{DS}=0\dots400\text{V}$
Gate source voltage (static)	V_{GS}	-20	-	20	V	static;
Gate source voltage (dynamic)	V_{GS}	-30	-	30	V	AC ($f>1\text{ Hz}$)
Power dissipation	P_{tot}	-	-	52	W	$T_C=25^\circ\text{C}$
Storage temperature	T_{stg}	-55	-	150	$^\circ\text{C}$	-
Operating junction temperature	T_j	-55	-	150	$^\circ\text{C}$	-
Mounting torque	-	-	-	-	Ncm	-
Continuous diode forward current	I_S	-	-	4.1	A	$T_C=25^\circ\text{C}$
Diode pulse current ²⁾	$I_{S,pulse}$	-	-	16	A	$T_C=25^\circ\text{C}$
Reverse diode dv/dt ⁴⁾	dv/dt	-	-	1	V/ns	$V_{DS}=0\dots400\text{V}$, $I_{SD}\leq 1.4\text{A}$, $T_j=25^\circ\text{C}$ see table 8
Maximum diode commutation speed	di/dt	-	-	50	A/ μs	$V_{DS}=0\dots400\text{V}$, $I_{SD}\leq 1.4\text{A}$, $T_j=25^\circ\text{C}$ see table 8
Insulation withstand voltage	V_{ISO}	-	-	n.a.	V	V_{rms} , $T_C=25^\circ\text{C}$, $t=1\text{min}$

¹⁾ Limited by $T_{j,max}$. Maximum Duty Cycle $D = 0.5$

²⁾ Pulse width t_p limited by $T_{j,max}$

³⁾ For further explanation please read AN - CoolMOS™ 700V P7 & 950V P7

⁴⁾ Identical low side and high side switch with identical R_G

2 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Thermal resistance, junction - case	R_{thJC}	-	-	2.4	°C/W	-
Thermal resistance, junction - ambient	R_{thJA}	-	-	62	°C/W	device on PCB, minimal footprint
Thermal resistance, junction - ambient for SMD version	R_{thJA}	-	35	45	°C/W	Device on 40mm*40mm*1.5mm epoxy PCB FR4 with 6cm² (one layer, 70µm thickness) copper area for drain connection and cooling. PCB is vertical without air stream cooling.
Soldering temperature, wave- & reflow soldering allowed	T_{sld}	-	-	260	°C	reflow MSL1

3 Electrical characteristics

at $T_j=25^\circ\text{C}$, unless otherwise specified

Table 4 Static characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Drain-source breakdown voltage	$V_{(BR)DSS}$	950	-	-	V	$V_{GS}=0V$, $I_D=1mA$
Gate threshold voltage	$V_{(GS)th}$	2.5	3	3.5	V	$V_{DS}=V_{GS}$, $I_D=0.14mA$
Zero gate voltage drain current	I_{DSS}	-	-	1	μA	$V_{DS}=950V$, $V_{GS}=0V$, $T_j=25^\circ\text{C}$ $V_{DS}=950V$, $V_{GS}=0V$, $T_j=150^\circ\text{C}$
Gate-source leakage current	I_{GSS}	-	-	1000	nA	$V_{GS}=20V$, $V_{DS}=0V$
Drain-source on-state resistance	$R_{DS(on)}$	-	1.03 2.291	1.2	Ω	$V_{GS}=10V$, $I_D=2.7A$, $T_j=25^\circ\text{C}$ $V_{GS}=10V$, $I_D=2.7A$, $T_j=150^\circ\text{C}$
Gate resistance	R_G	-	1	-	Ω	$f=250kHz$, open drain

Table 5 Dynamic characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input capacitance	C_{iss}	-	478	-	pF	$V_{GS}=0V$, $V_{DS}=400V$, $f=250kHz$
Output capacitance	C_{oss}	-	7	-	pF	$V_{GS}=0V$, $V_{DS}=400V$, $f=250kHz$
Effective output capacitance, energy related ¹⁾	$C_{o(er)}$	-	12	-	pF	$V_{GS}=0V$, $V_{DS}=0...400V$
Effective output capacitance, time related ²⁾	$C_{o(tr)}$	-	120	-	pF	$I_D=\text{constant}$, $V_{GS}=0V$, $V_{DS}=0...400V$
Turn-on delay time	$t_{d(on)}$	-	7	-	ns	$V_{DD}=400V$, $V_{GS}=13V$, $I_D=2.7A$, $R_G=10.2\Omega$; see table 9
Rise time	t_r	-	10	-	ns	$V_{DD}=400V$, $V_{GS}=13V$, $I_D=2.7A$, $R_G=10.2\Omega$; see table 9
Turn-off delay time	$t_{d(off)}$	-	36	-	ns	$V_{DD}=400V$, $V_{GS}=13V$, $I_D=2.7A$, $R_G=10.2\Omega$; see table 9
Fall time	t_f	-	12	-	ns	$V_{DD}=400V$, $V_{GS}=13V$, $I_D=2.7A$, $R_G=10.2\Omega$; see table 9

Table 6 Gate charge characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gate to source charge	Q_{gs}	-	2	-	nC	$V_{DD}=760V$, $I_D=2.7A$, $V_{GS}=0$ to $10V$
Gate to drain charge	Q_{gd}	-	5	-	nC	$V_{DD}=760V$, $I_D=2.7A$, $V_{GS}=0$ to $10V$
Gate charge total	Q_g	-	15	-	nC	$V_{DD}=760V$, $I_D=2.7A$, $V_{GS}=0$ to $10V$
Gate plateau voltage	$V_{plateau}$	-	4.4	-	V	$V_{DD}=760V$, $I_D=2.7A$, $V_{GS}=0$ to $10V$

¹⁾ $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400V

²⁾ $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400V

Table 7 Reverse diode characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Diode forward voltage	V_{SD}	-	0.9	-	V	$V_{GS}=0V$, $I_F=2.7A$, $T_J=25^{\circ}C$
Reverse recovery time	t_{rr}	-	560	-	ns	$V_R=400V$, $I_F=1.4A$, $di_F/dt=50A/\mu s$; see table 8
Reverse recovery charge	Q_{rr}	-	3	-	μC	$V_R=400V$, $I_F=1.4A$, $di_F/dt=50A/\mu s$; see table 8
Peak reverse recovery current	I_{rrm}	-	8	-	A	$V_R=400V$, $I_F=1.4A$, $di_F/dt=50A/\mu s$; see table 8

4 Electrical characteristics diagrams

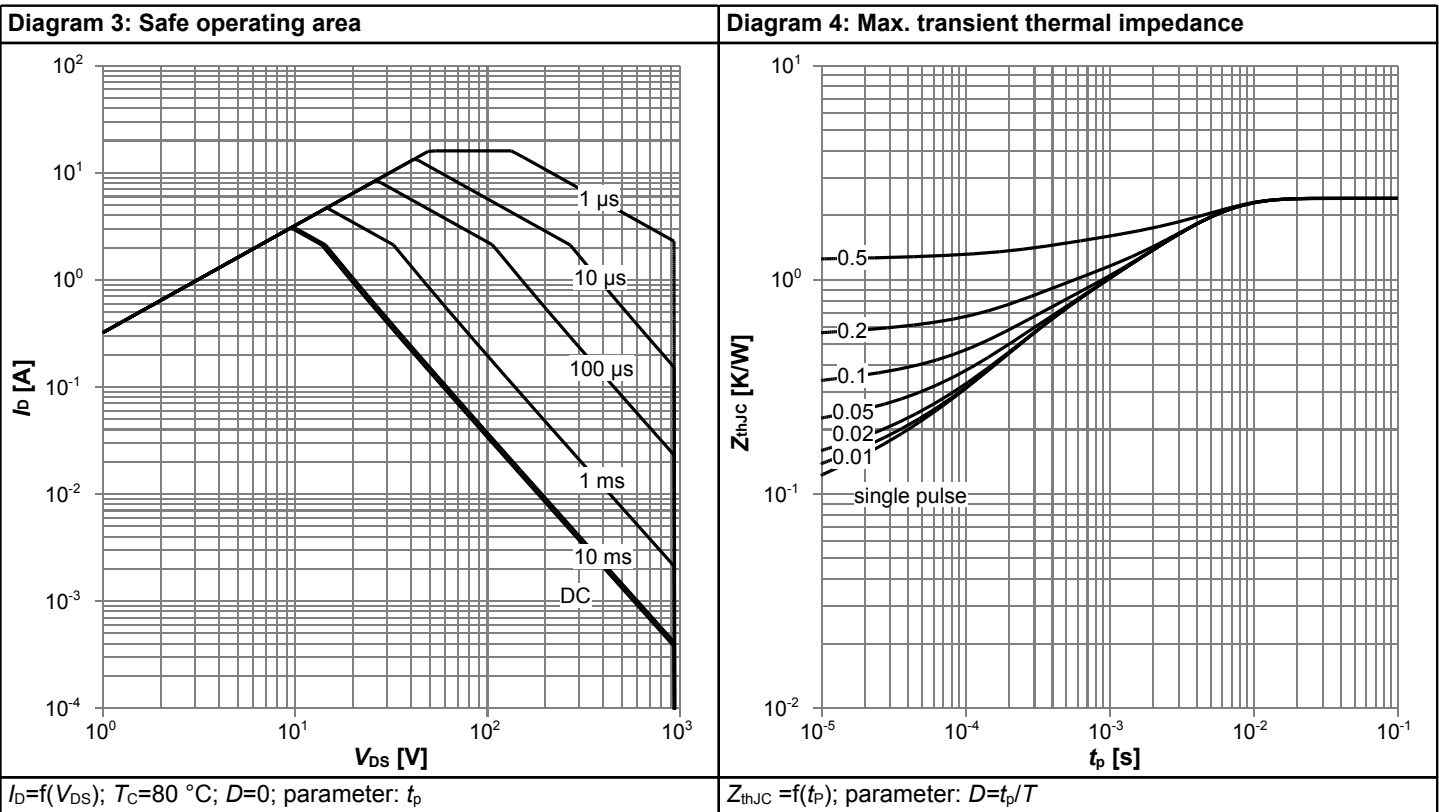
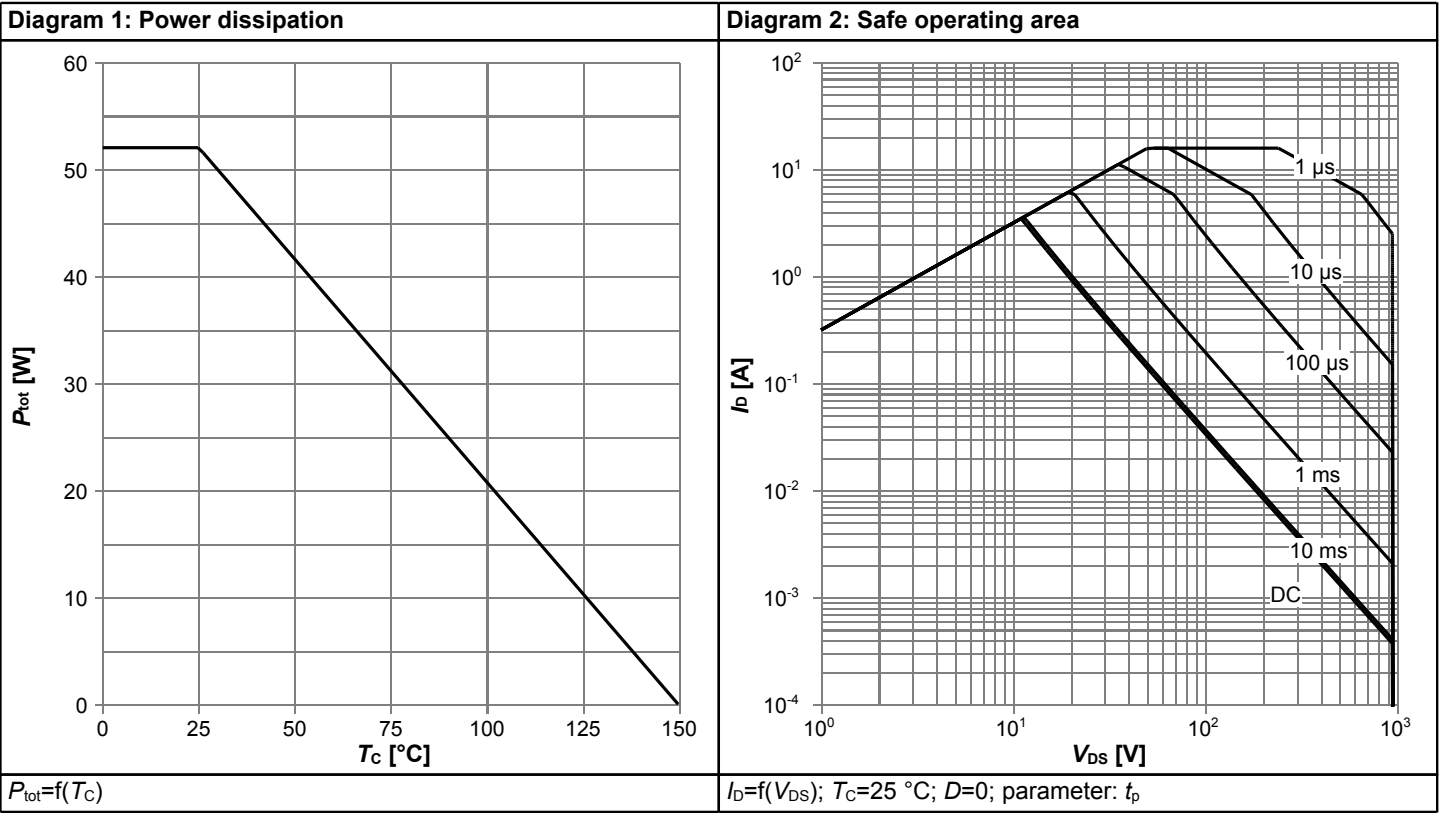
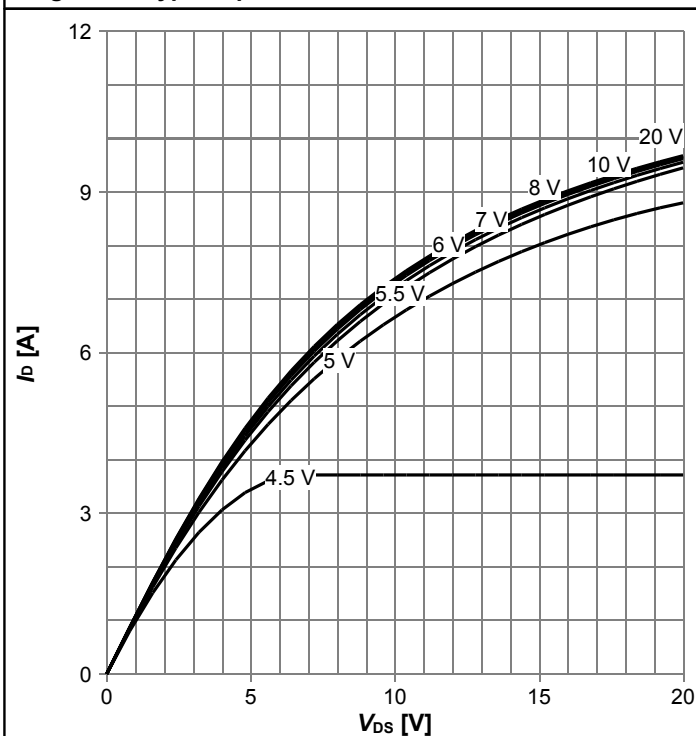
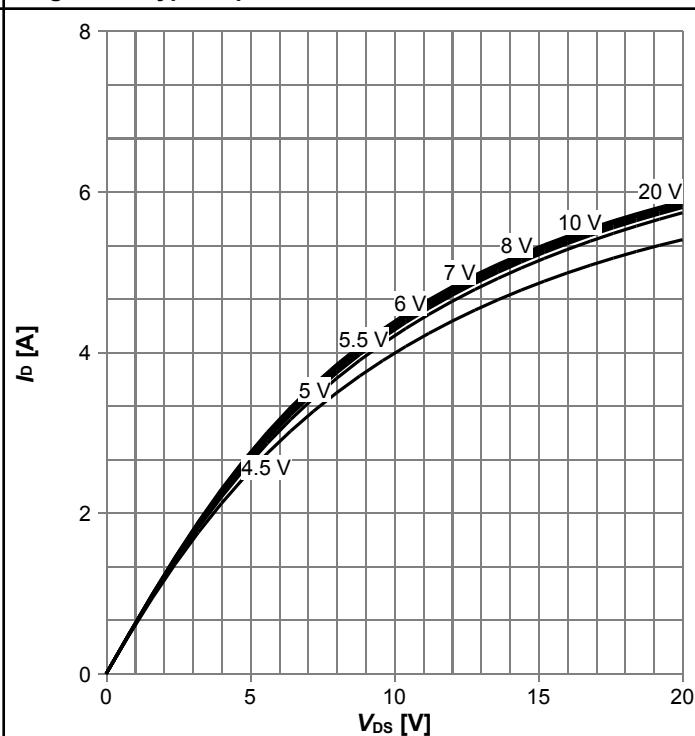


Diagram 5: Typ. output characteristics



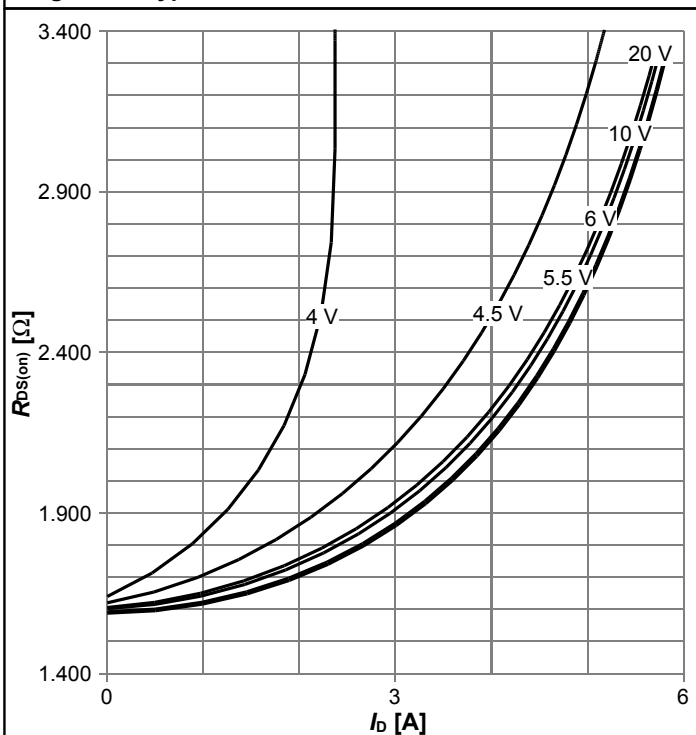
$I_D = f(V_{DS})$; $T_j = 25\text{ °C}$; parameter: V_{GS}

Diagram 6: Typ. output characteristics



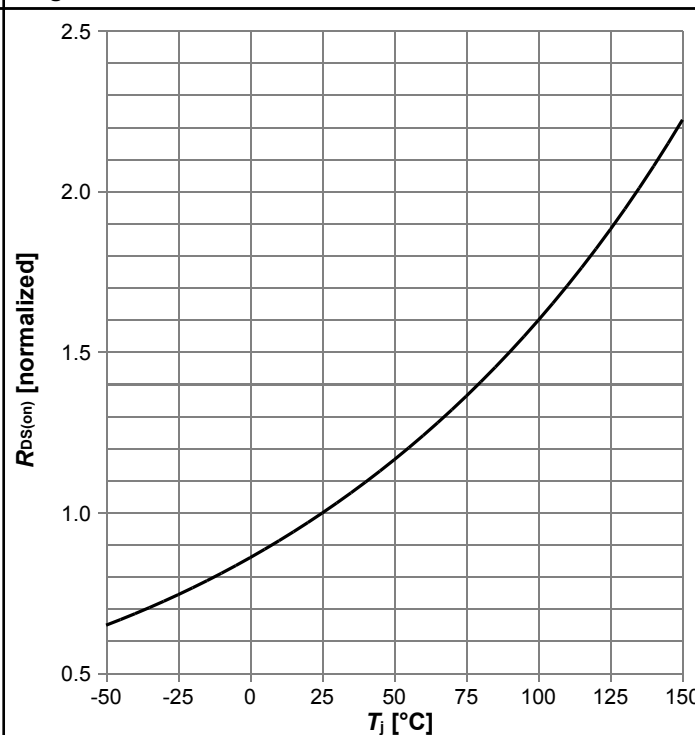
$I_D = f(V_{DS})$; $T_j = 125\text{ °C}$; parameter: V_{GS}

Diagram 7: Typ. drain-source on-state resistance



$R_{DS(on)} = f(I_D)$; $T_j = 125\text{ °C}$; parameter: V_{GS}

Diagram 8: Drain-source on-state resistance



$R_{DS(on)} = f(T_j)$; $I_D = 2.7\text{ A}$; $V_{GS} = 10\text{ V}$

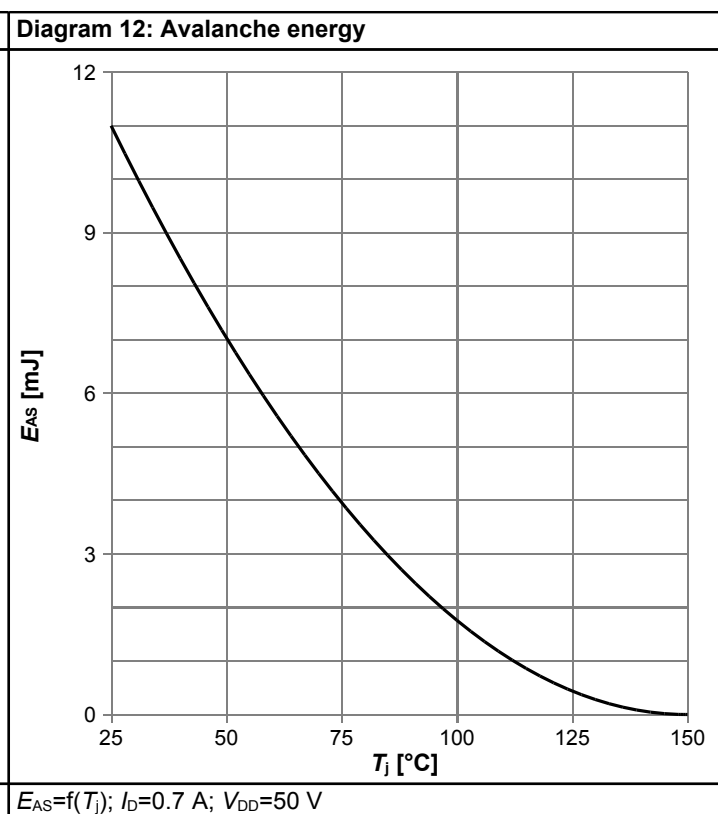
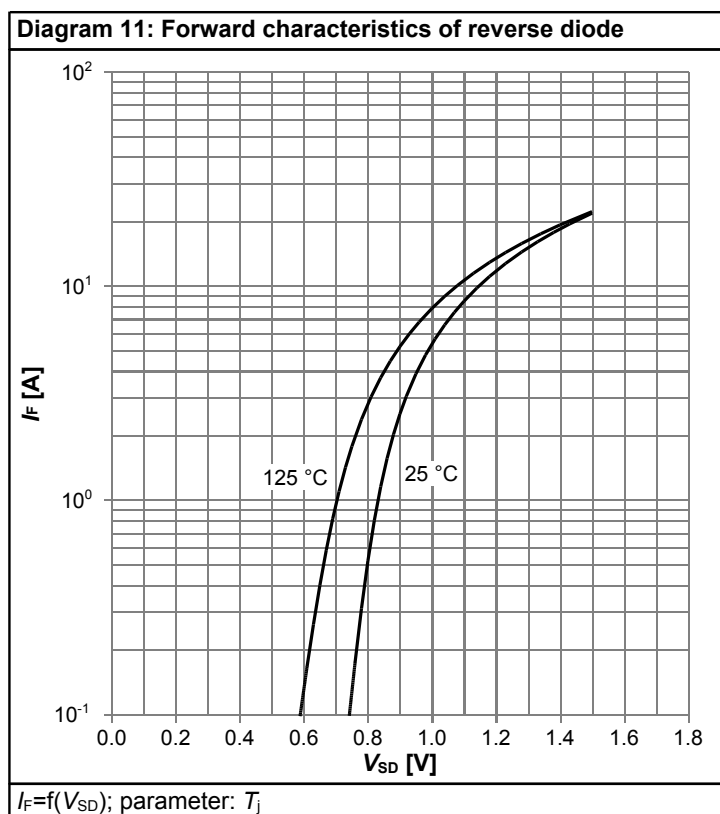
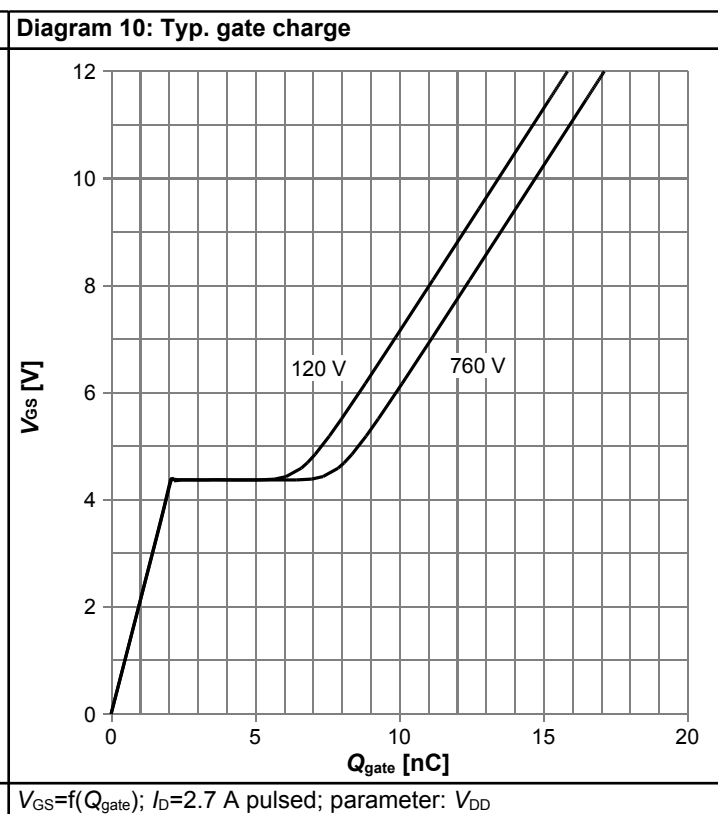
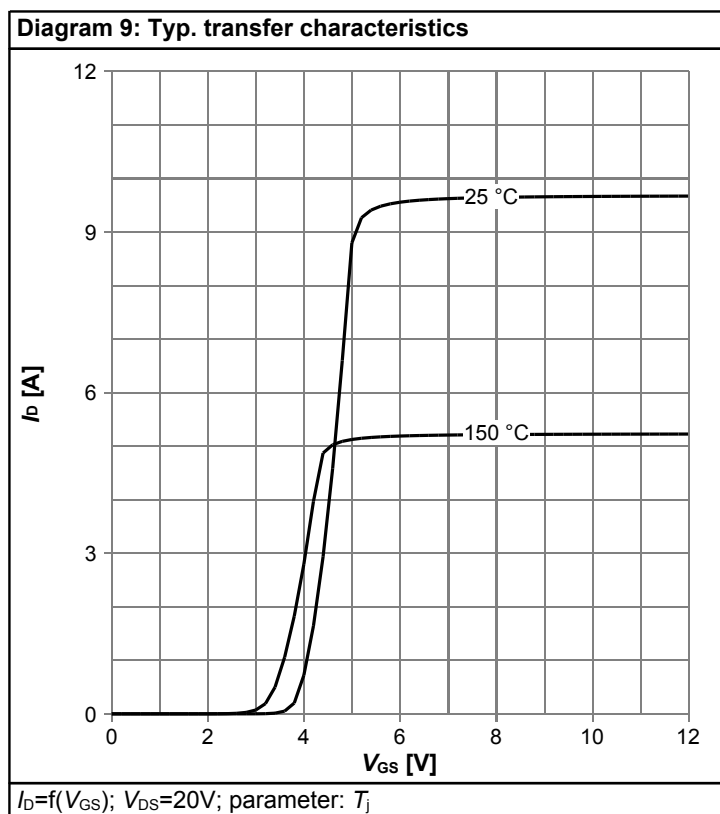
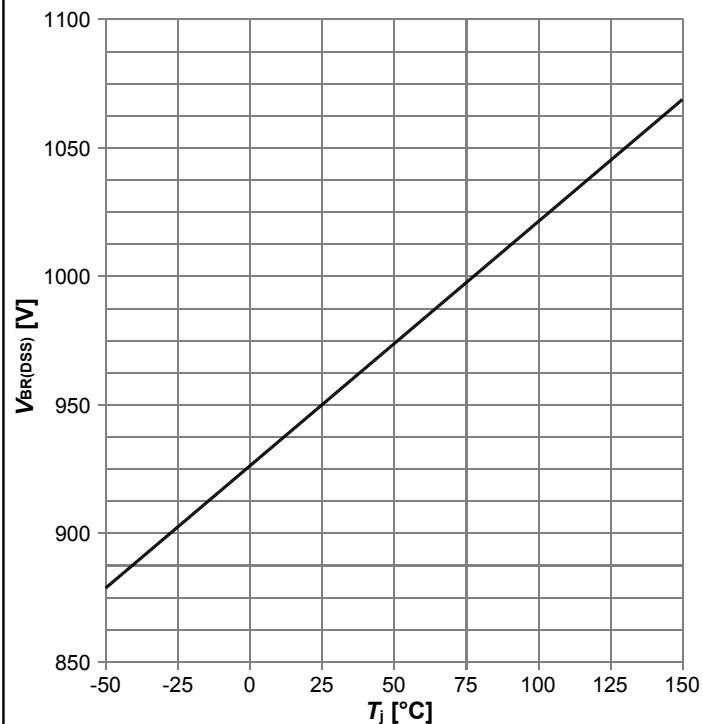
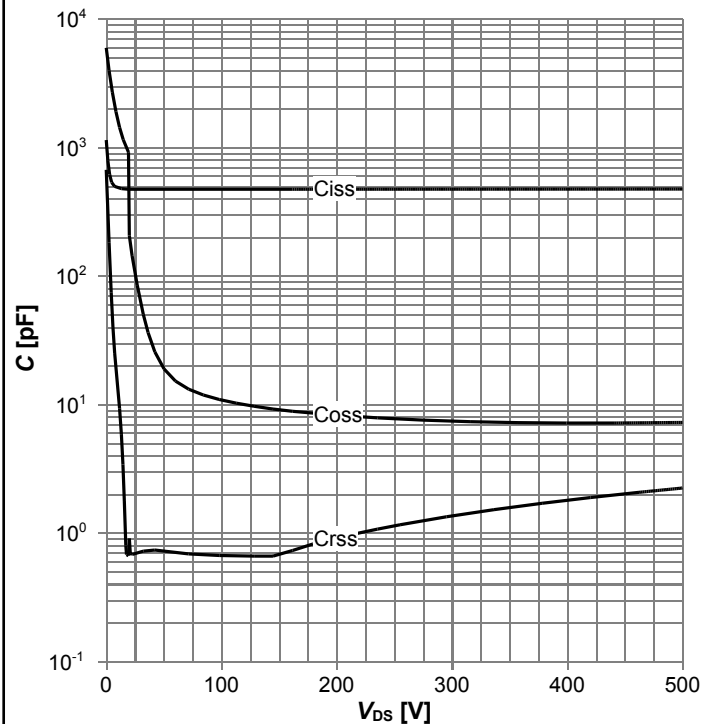


Diagram 13: Drain-source breakdown voltage



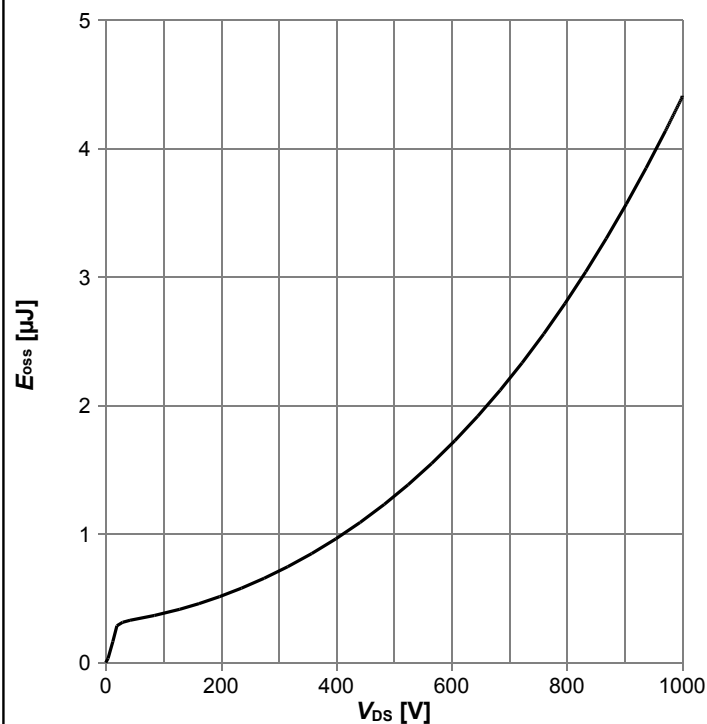
$V_{BR(DSS)} = f(T_J); I_D = 1 \text{ mA}$

Diagram 14: Typ. capacitances



$C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 250 \text{ kHz}$

Diagram 15: Typ. Coss stored energy



$E_{oss} = f(V_{DS})$

5 Test Circuits

Table 8 Diode characteristics

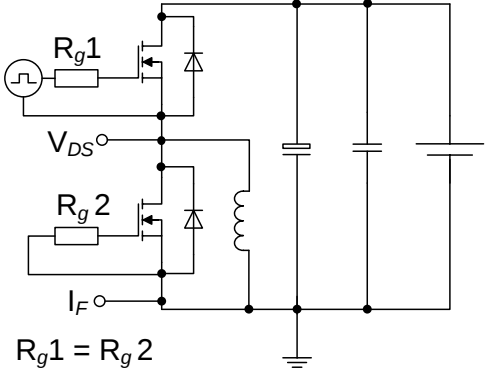
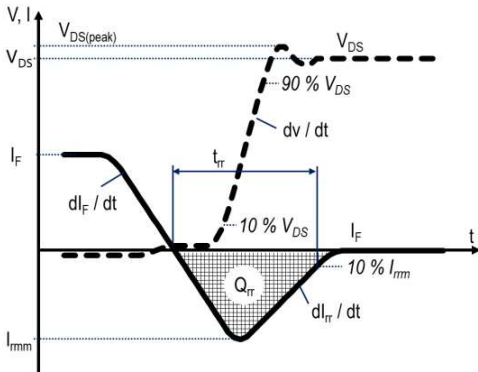
Test circuit for diode characteristics	Diode recovery waveform
 $R_{g1} = R_{g2}$	

Table 9 Switching times

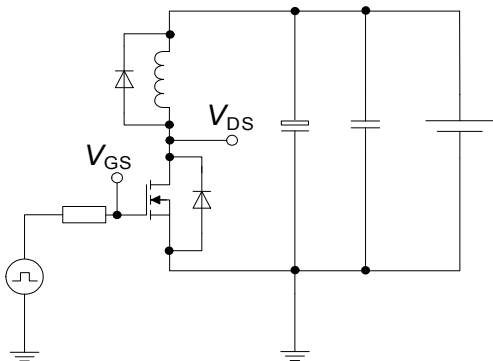
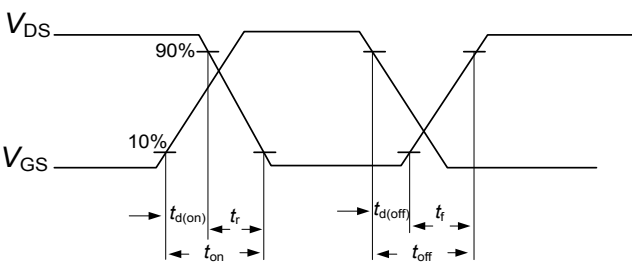
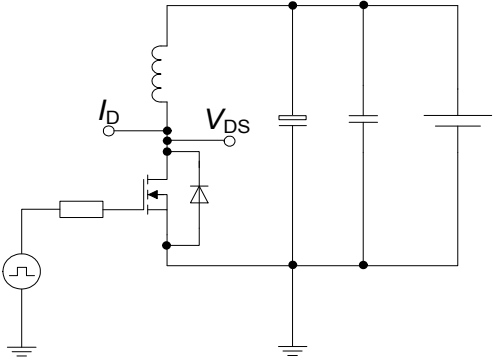
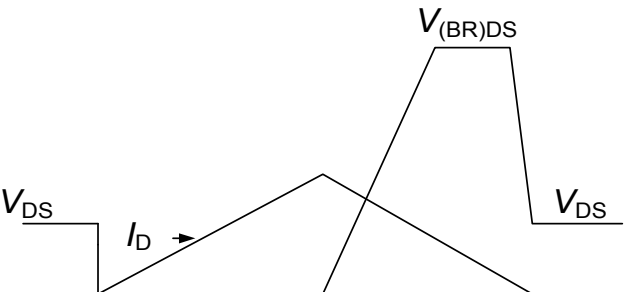
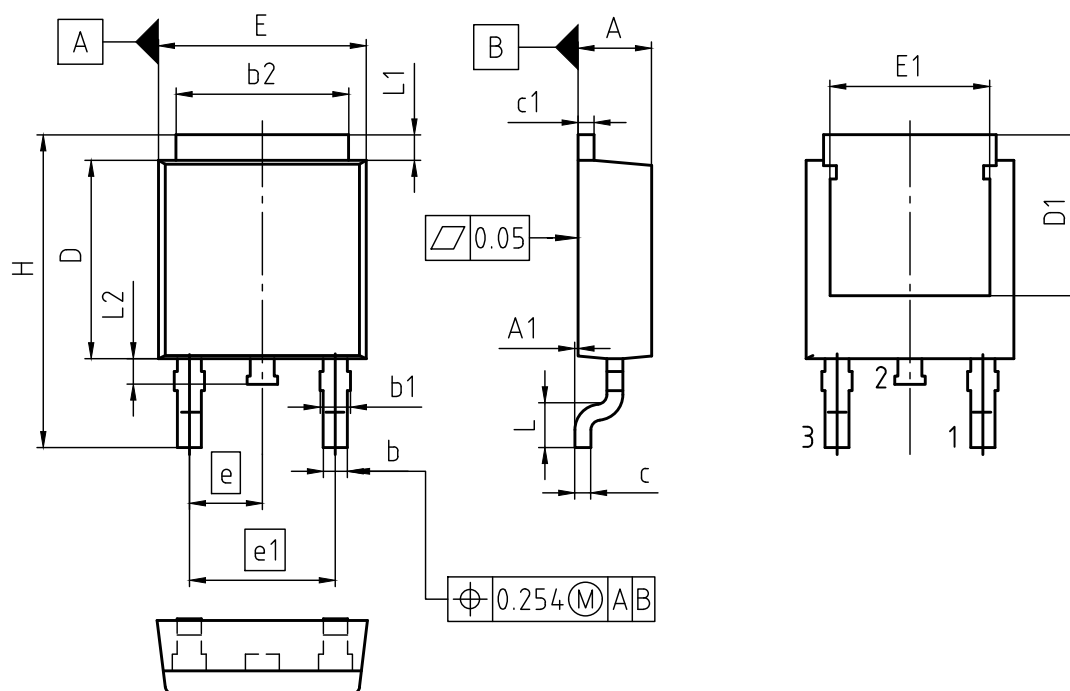
Switching times test circuit for inductive load	Switching times waveform
	

Table 10 Unclamped inductive load

Unclamped inductive load test circuit	Unclamped inductive waveform
	

6 Package Outlines



PACKAGE - GROUP NUMBER: PG-TO252-3-U02		
REVISION: 01		DATE: 23.11.2021
DIMENSIONS	MILLIMETERS	
	MIN.	MAX.
A	2.16	2.41
A1	0.00	0.15
b	0.64	0.89
b1	0.65	1.15
b2	4.95	5.50
c	0.46	0.61
c1	0.40	0.98
D	5.97	6.22
D1	5.02	5.84
E	6.35	6.73
E1	4.32	5.50
e	2.29	
e1	4.57	
N	3	
H	9.40	10.48
L	1.18	1.78
L1	0.89	1.27
L2	0.51	1.02

ALL DIMENSIONS REFER TO JEDEC
STANDARD TO-252 AND DO NOT INCLUDE MOLD
FLASH OR PROTRUSIONS.

Figure 1 Outline PG-TO252-3, dimensions in mm

7 Appendix A

Table 11 Related Links

- IFX CoolMOS P7 Webpage: www.infineon.com
- IFX CoolMOS P7 application note: www.infineon.com
- IFX CoolMOS P7 simulation model: www.infineon.com
- IFX Design tools: www.infineon.com

Revision History

IPD95R1K2P7

Revision: 2022-01-12, Rev. 2.3

Previous Revision

Revision	Date	Subjects (major changes since last revision)
2.0	2018-05-30	Release of final version
2.1	2018-06-04	Final
2.2	2020-05-26	Updated package/symbol drawing, and product validation
2.3	2022-01-12	Updated Package Outlines

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